
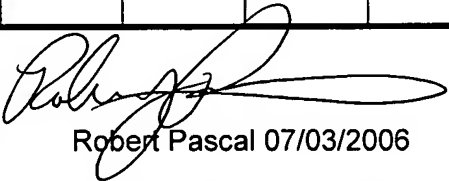
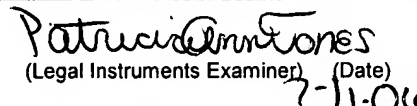


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/510,254	DEKKERS ET AL.	
	Examiner	Art Unit	
	Hieu P. Nguyen	2817	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
330		252			330	260			
INTERNATIONAL CLASSIFICATION									
H	0	3	F	3/45					
				/					
				/					
				/					
				/					
/Hieu Nguyen 07/03/2006 (Assistant Examiner) (Date)					 Robert Pascal 07/03/2006 (Primary Examiner) (Date)			Total Claims Allowed: 10	
 Patricia Amato (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig. 5

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
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